

Electro-Adhesive Tubular Clutch for Variable-Stiffness Robots

Yi Sun

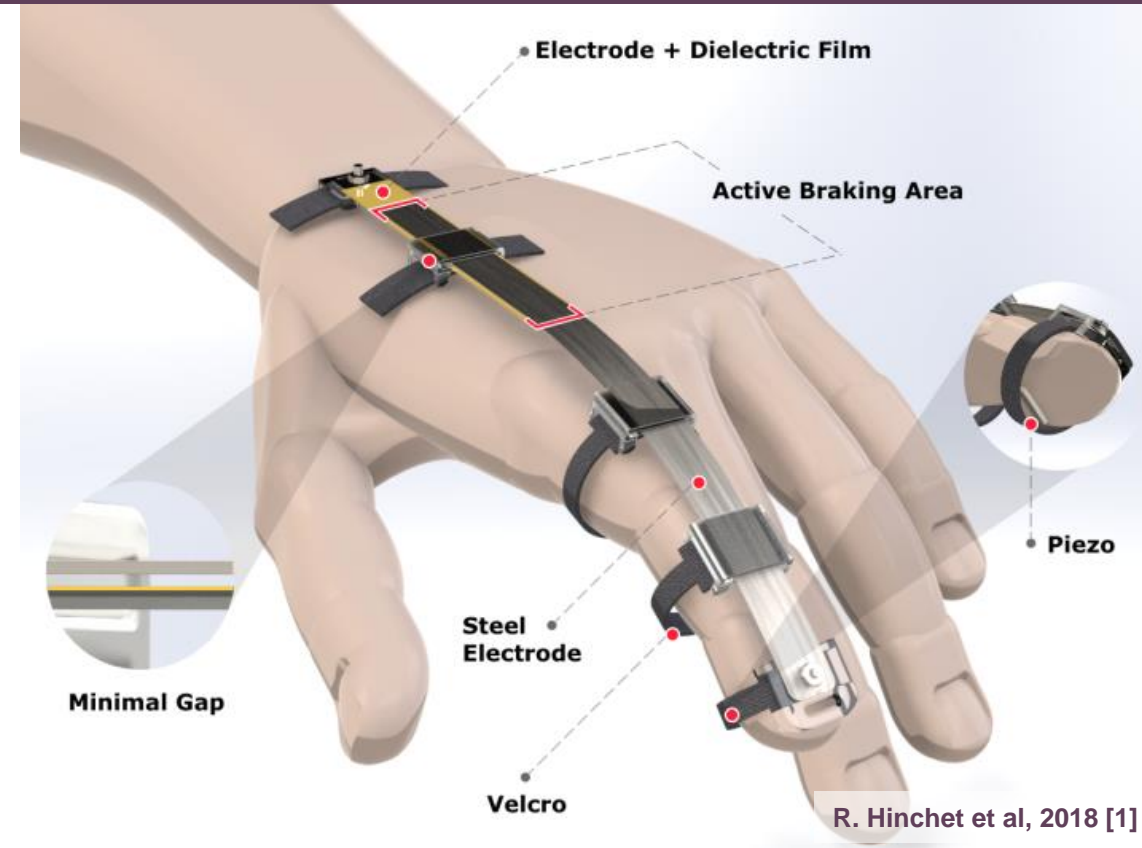
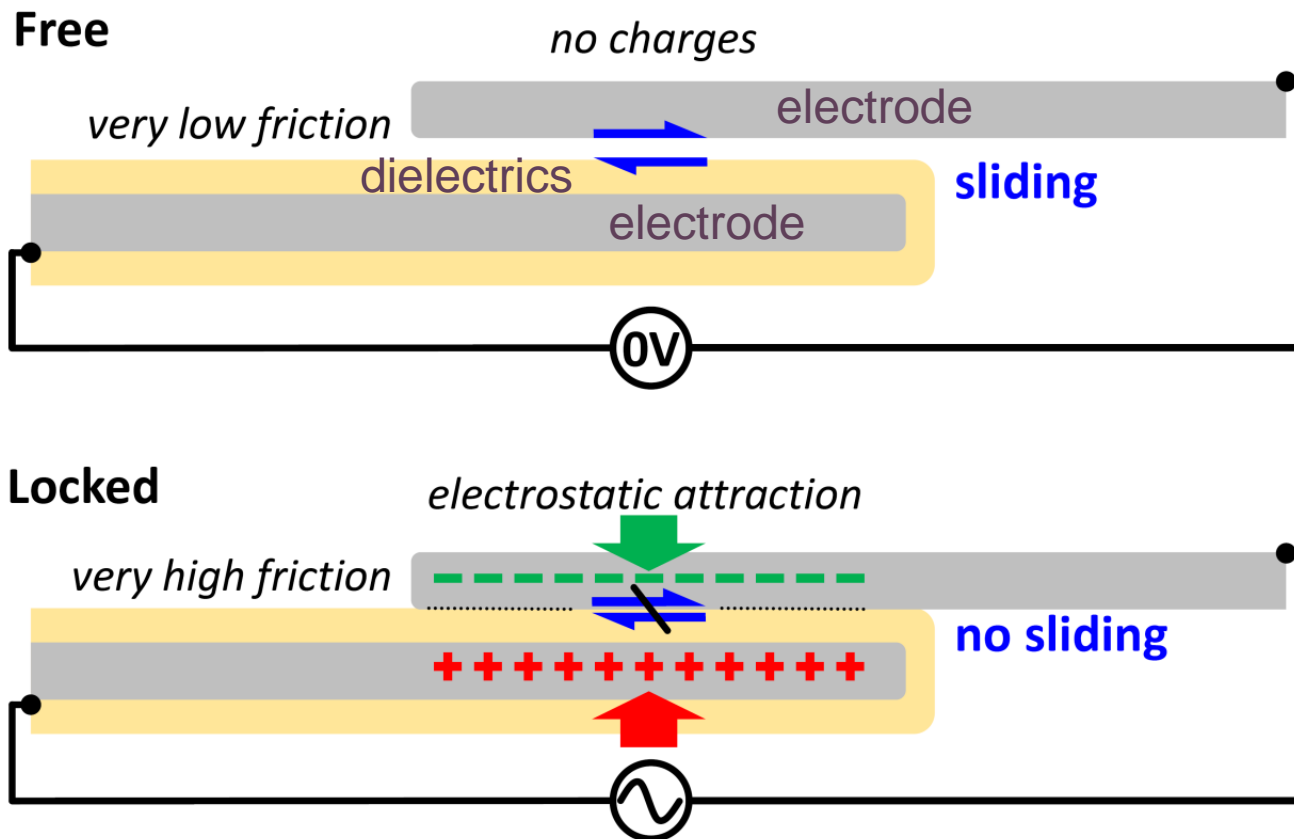
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École Polytechnique Fédérale de Lausanne

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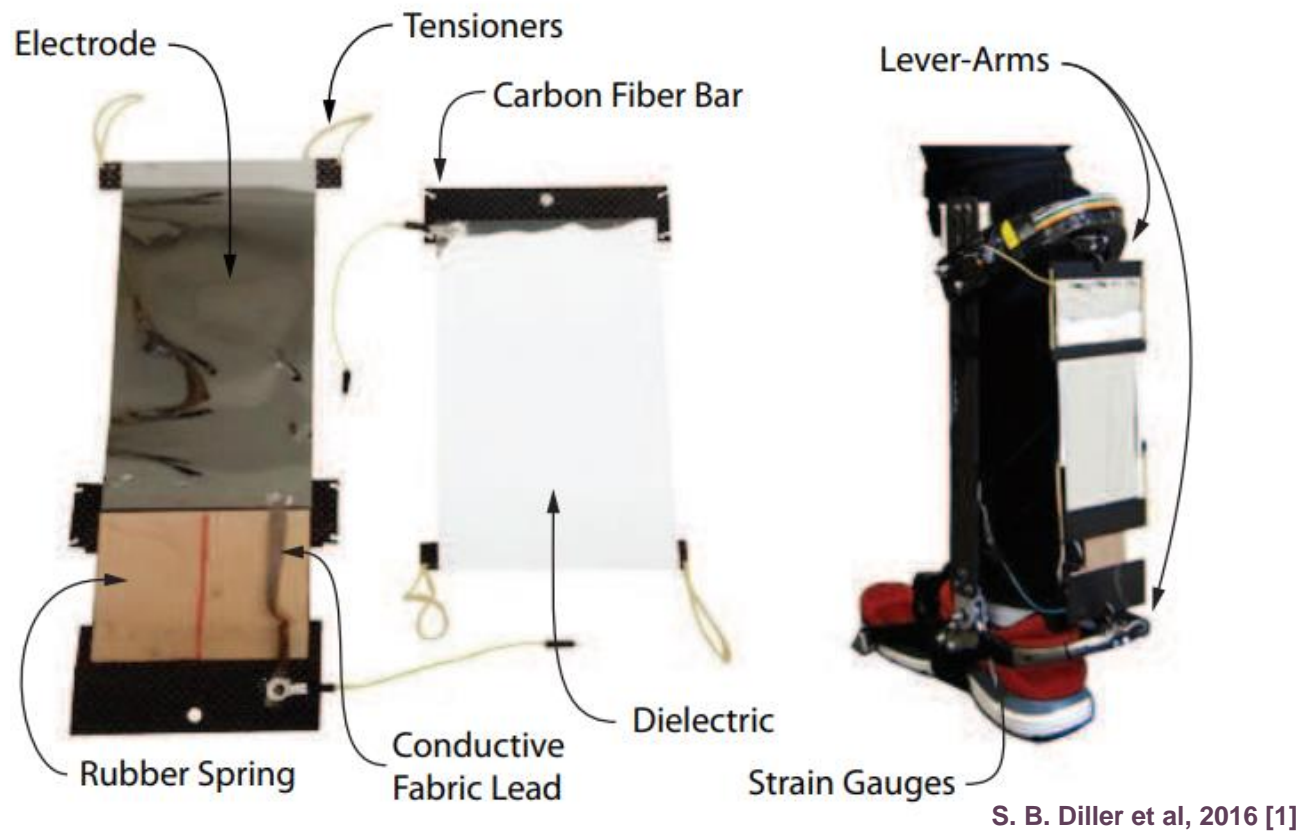
Introduction

- Electro-adhesive (EA) clutch



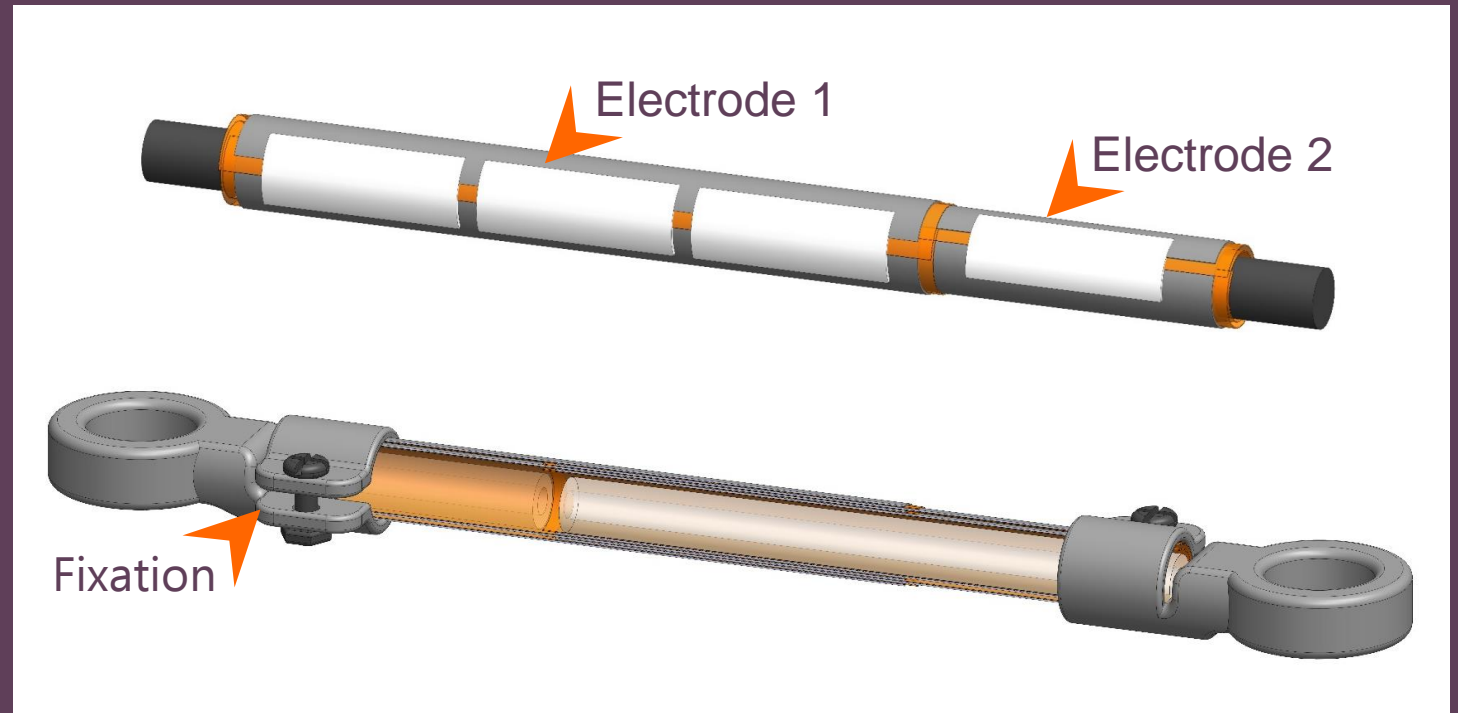
Introduction

- Disadvantages of EA clutches

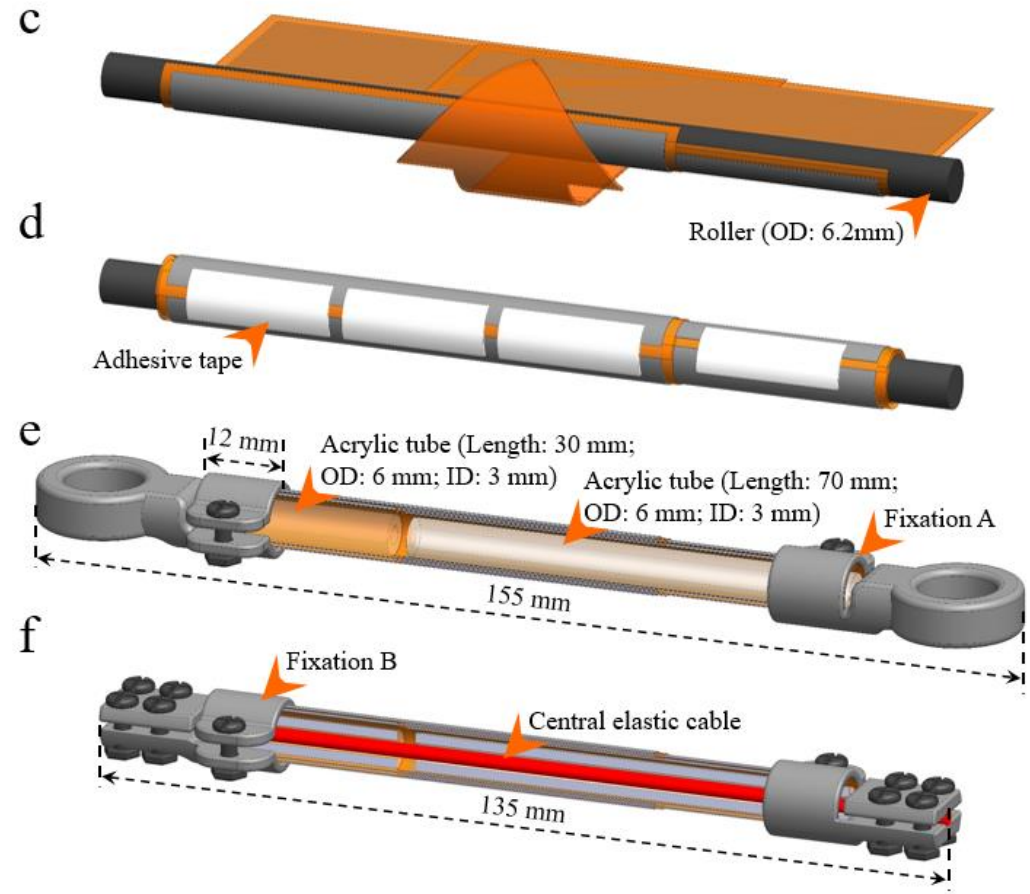
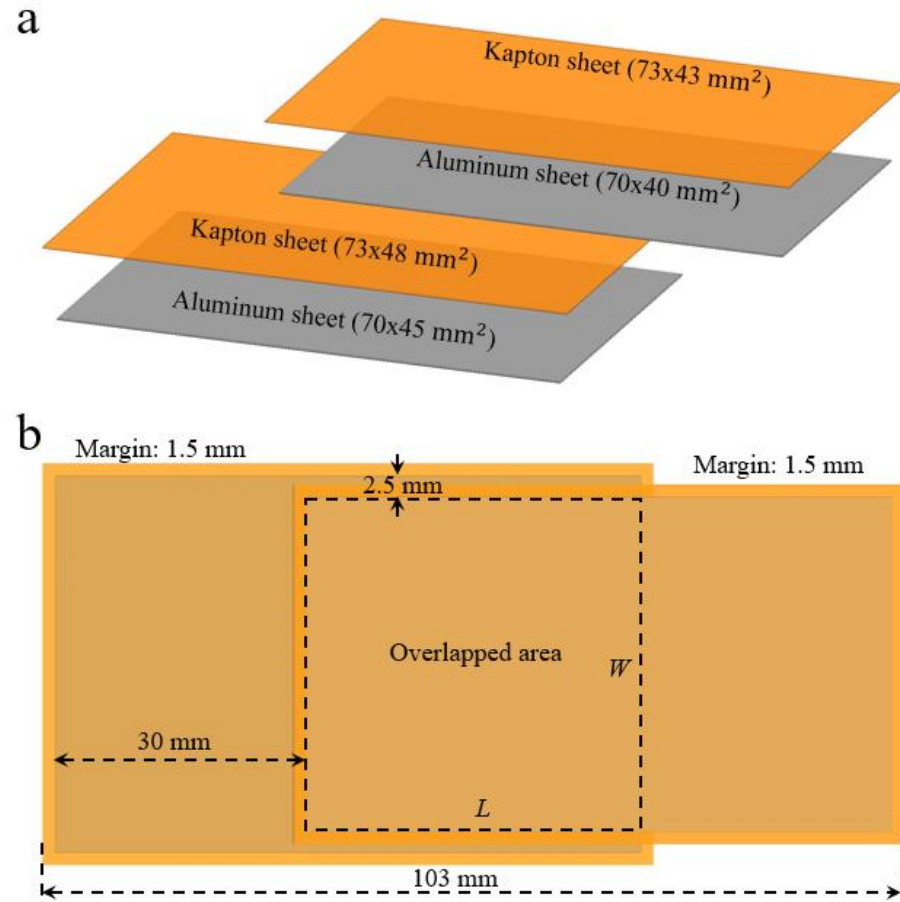


EA Tubular Clutch (EATC)

- EATC benefits
 - Higher forces is achieved with minimum size increase
 - Requires no guiding parts for directional sliding
 - The roll serves as a natural encapsulation to avoid dust contamination
 - Stress in the roll keel the electrode layers in firm contact for reliable performance



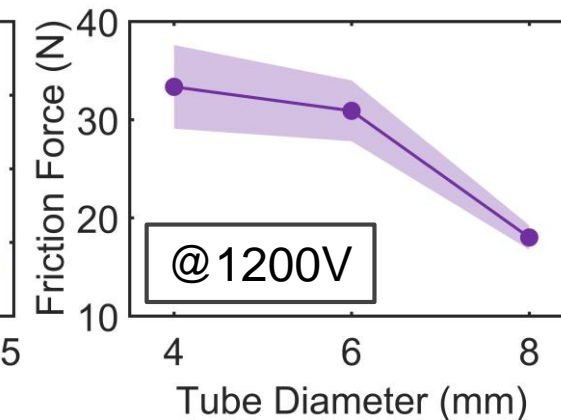
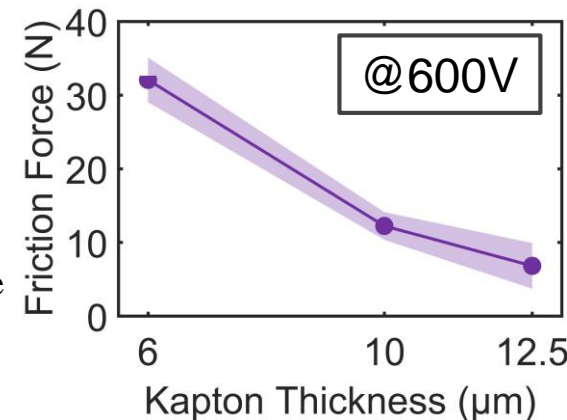
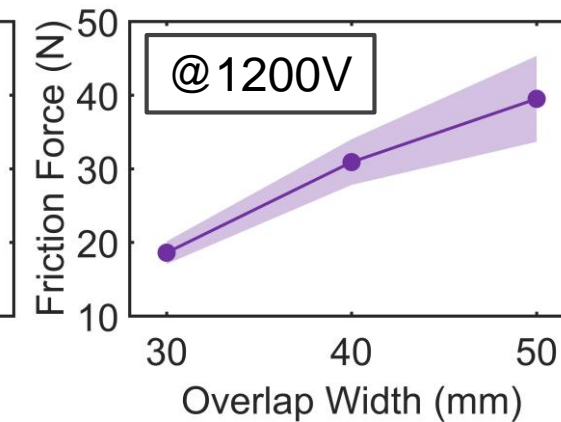
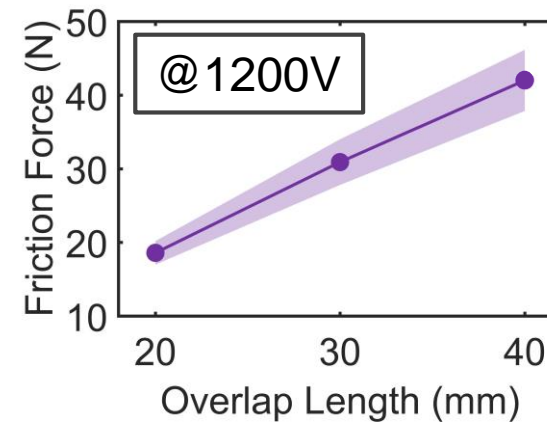
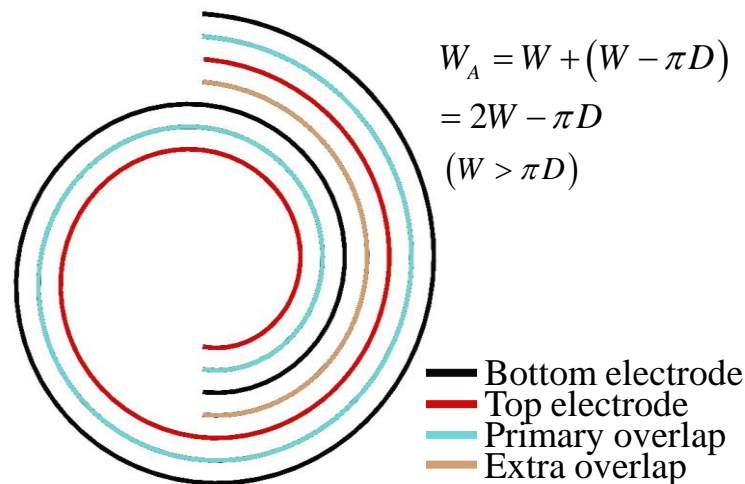
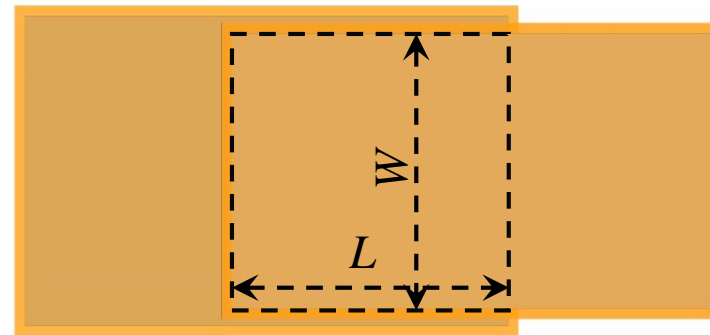
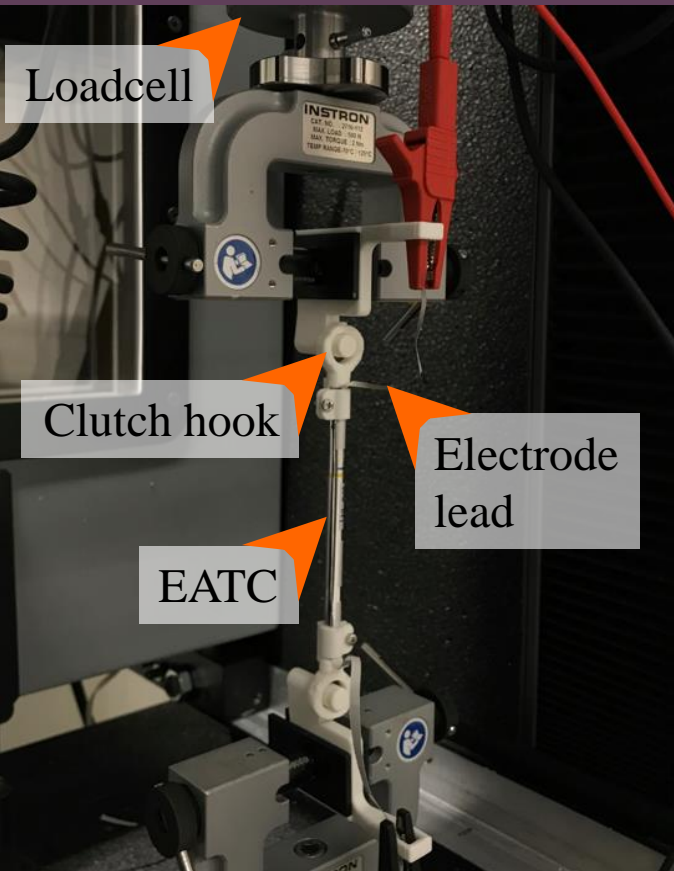
EATC Fabrication



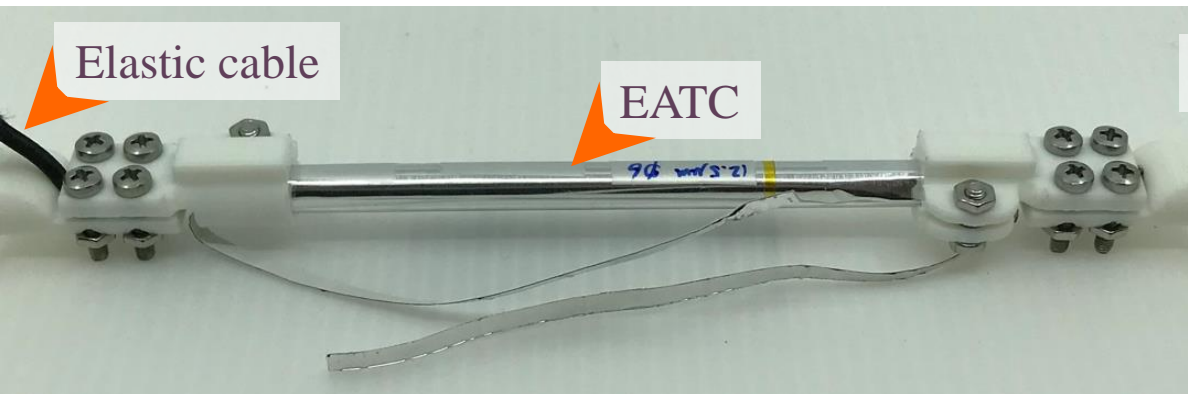
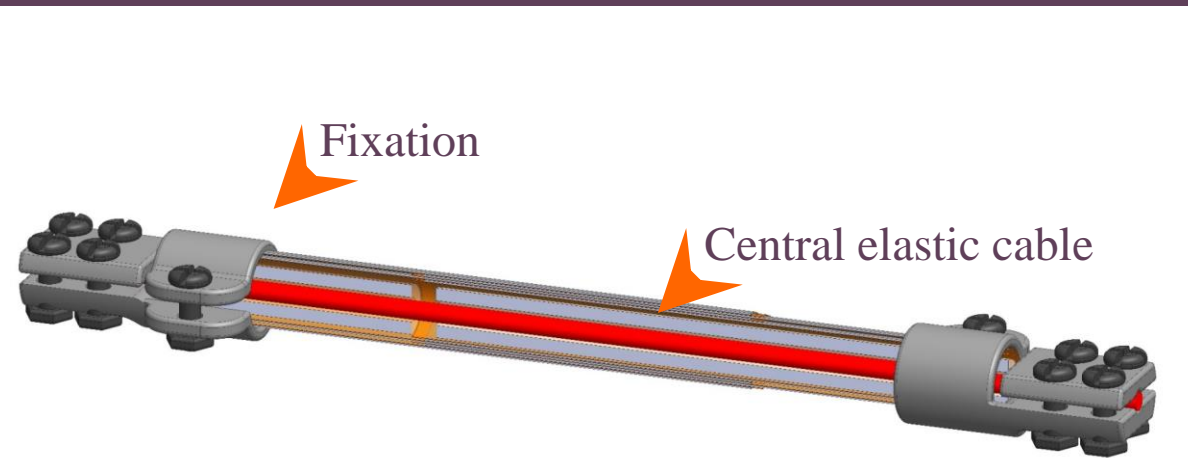
EATC Characterization

- Vary length and Kapton layer thickness.

$$F_f = \mu \times F_{EA} = \mu \cdot \frac{\epsilon_0 \cdot \epsilon_r \cdot A \cdot V^2}{2 \cdot d^2}$$

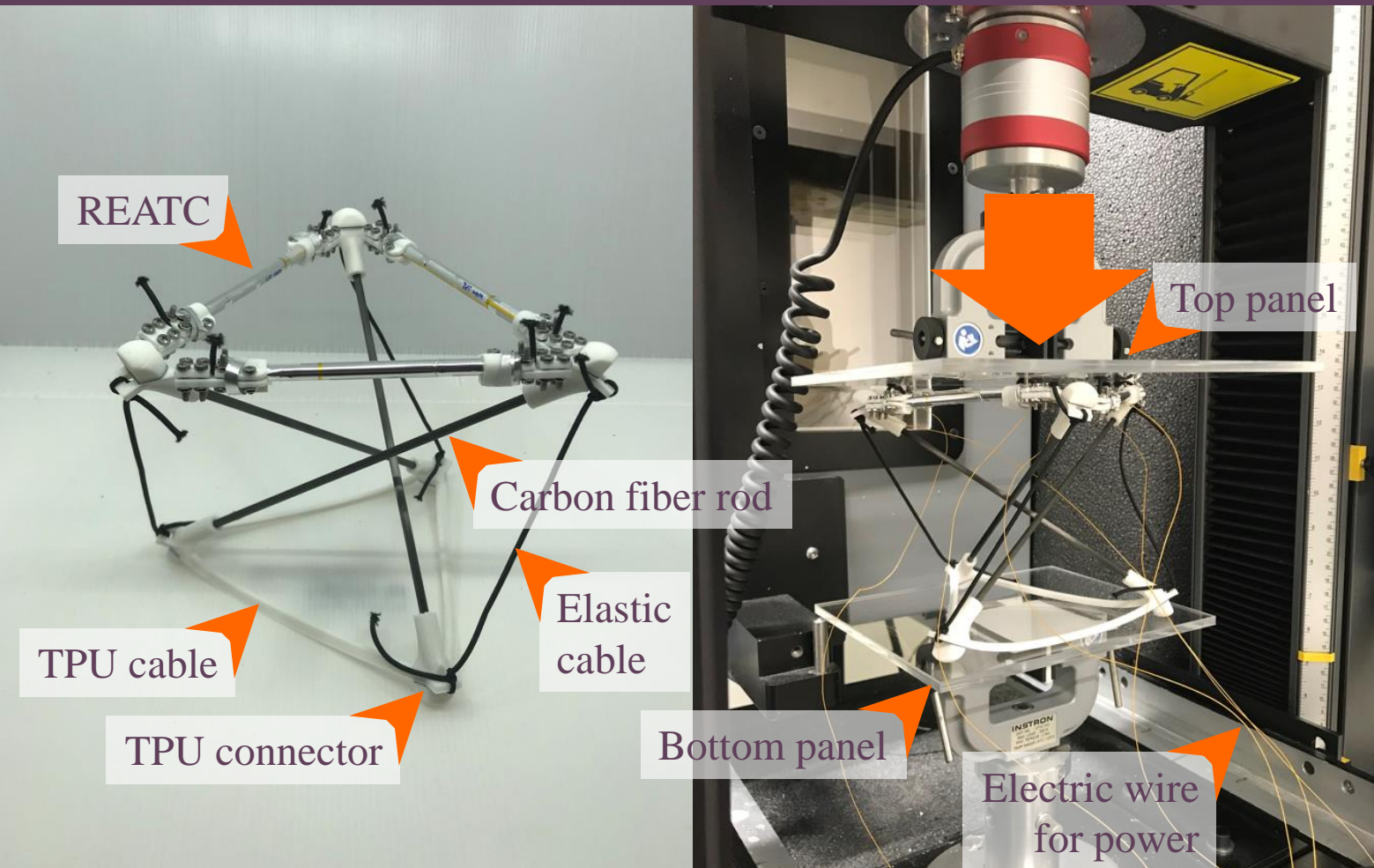


Retractable EATC (REATC)



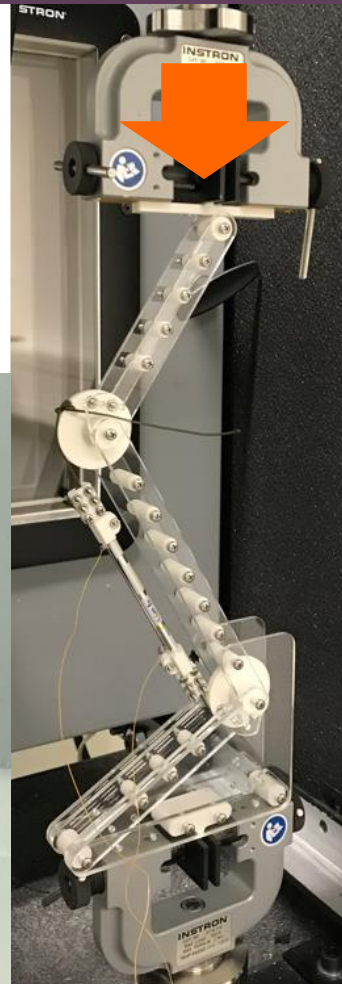
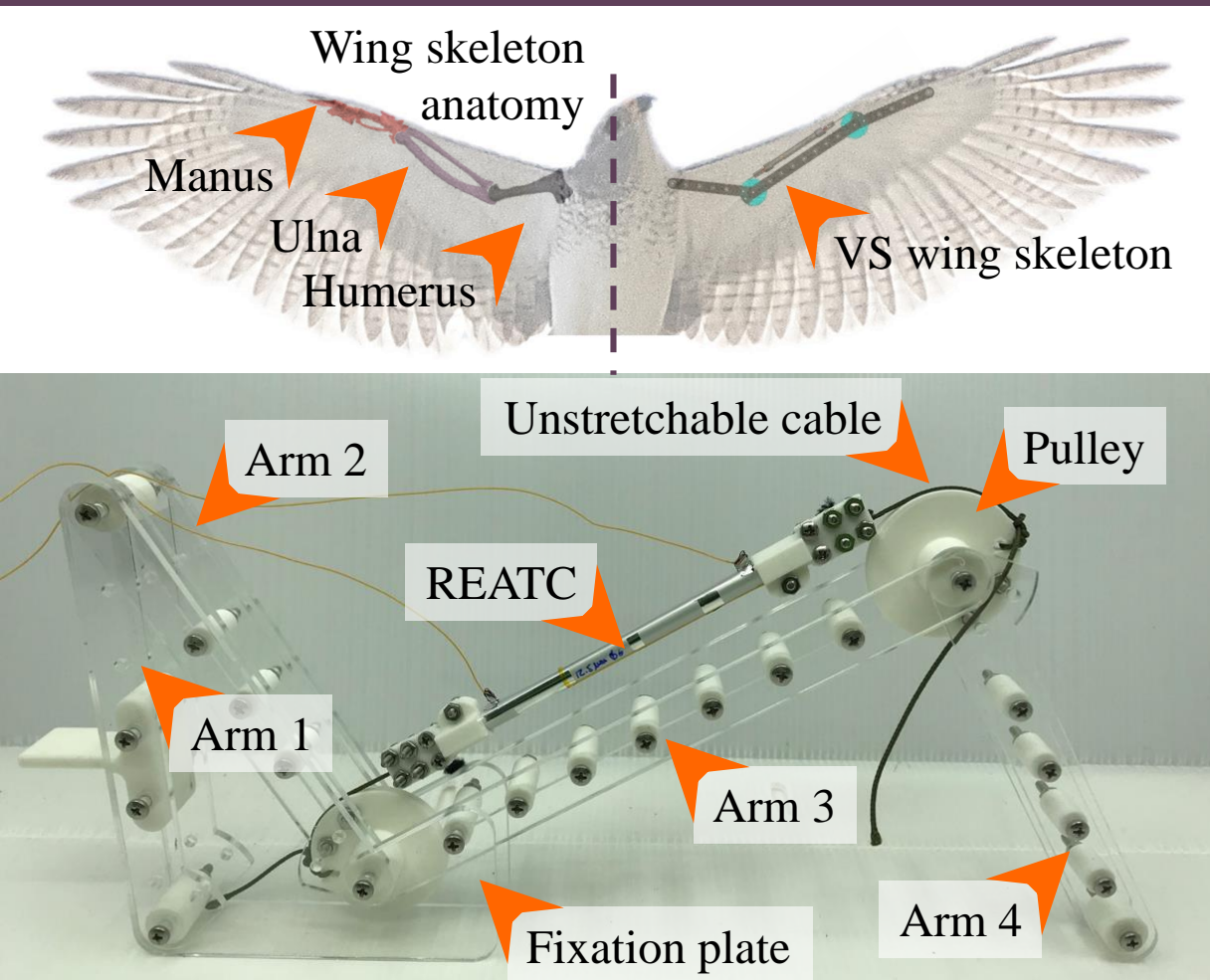
- Stiffness
 - 0.0119 N/mm @ 0V
 - 31 N/mm @ 1200V
 - Change factor – 260.1
- Load-bearing capacity
 - 3.58 N @ 0V
 - 31.77 N @ 1200V
 - Change factor – 8,88

Variable Stiffness (VS) Tensegrity



- Stiffness
 - 1,12 N/mm @ 0V
 - 14,8 N/mm @ 1200V
 - Change factor – 13,21
- Load-bearing capacity
 - 17,62 N @ 0V
 - 147,29 N @ 1200V
 - Change factor – 8,36

VS Wing skeleton



• Stiffness

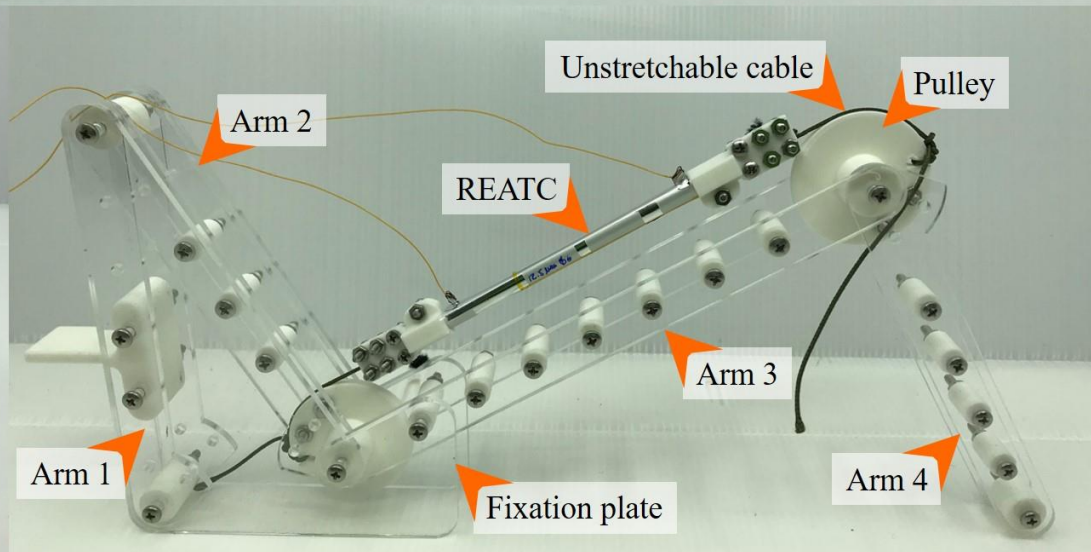
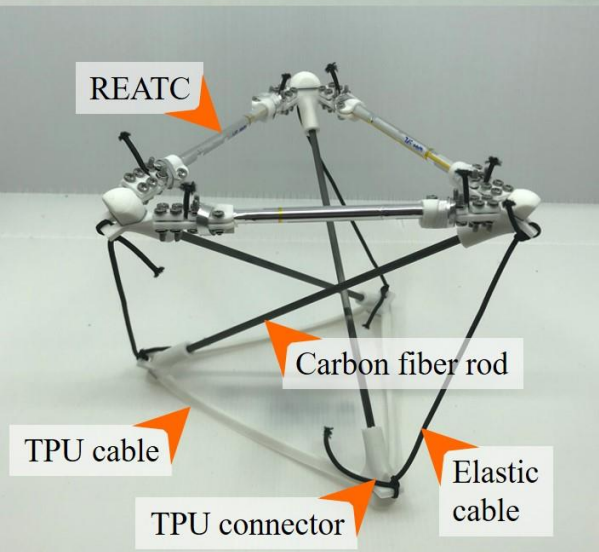
- 0.0127 N/mm @ 0V
- 0,383 N/mm @ 1200V
- Change factor – 30,16

• Load-bearing capacity

- 0,789 N @ 0V
- 10,96 N @ 1200V
- Change factor – 13,89

Conclusion

Electro-Adhesive Tubular Clutch and Its Applications



- Compact (3.2cm^3) and lightweight (10g)
- Scalable in size and brake force
- Suitable for force transmission via tensioned cables
- Targeted on lightweight and compact systems for variable stiffness functions



End of Presentation

Thank you very much

Q&A

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